Se	arch No	otes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/791,180	FREKER ET AL.	
Examiner	Art Unit	
Tse Chen	2116	

	SEARCHED			
Class	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
text seach only: 1510 BUTFER REQUIRED	12/23/06	TSE